

The following listing of the claims is provided for the Examiner's convenience. No amendments have been made.

Claims 1-14 (canceled)

Claim 19 (previously presented): The scanning microscope as recited in claim 15 further comprising an objective lens configured to focus the illuminating light beam onto the sample.

Claim 20 (previously presented): The scanning microscope as recited in claim 19 wherein the objective lens is configured to focus the sub-light beam onto the sample.

Claim 21 (previously presented): The scanning microscope as recited in claim 19 further comprising a further objective lens configured to focus the sub-light beam onto the sample.

Claim 22 (previously presented): The scanning microscope as recited in claim 15 wherein the beam guiding device includes an optical waveguide.

Claim 23 (previously presented): The scanning microscope as recited in claim 15 wherein the sub-light beam has a specific polarization property.

Claim 24 (previously presented): The scanning microscope as recited in claim 23 further comprising a polarization control device disposed between the at least one light source and the acousto-optical element.

Claim 25 (previously presented): The scanning microscope as recited in claim 24 wherein the polarization control device includes a $\lambda/2$ plate.

Claim 26 (previously presented): The scanning microscope as recited in claim 15 further comprising a dispersion compensation device configured to compensate for spatial spectral dispersion, caused by the acousto-optical element, of at least one of the sub-light beam and the illuminating light beam.

Claim 27 (previously presented): The scanning microscope as recited in claim 26 wherein the dispersion compensation device includes at least one of a prism, a grating and a further acousto-optical element.

Claim 28 (previously presented): The scanning microscope as recited in claim 15 wherein the acousto-optical element is configured to direct, to a detector, detection light emanating from the sample.

Claim 29 (previously presented): The scanning microscope as recited in claim 15 further comprising an excitation pinhole configured to support confocal scanning microscopy.